Fig. 1

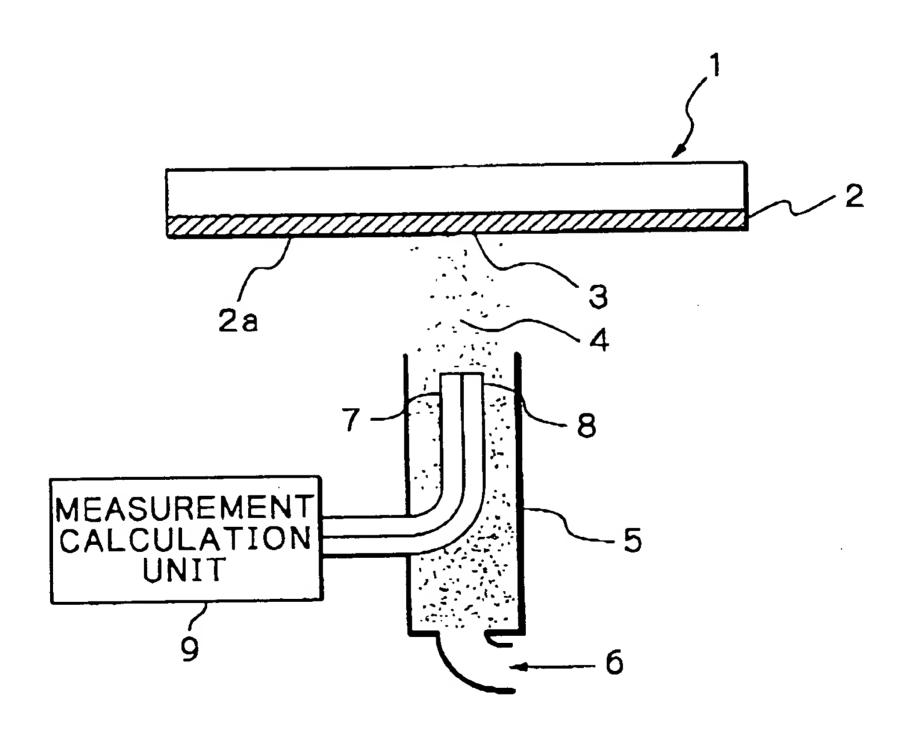


Fig. 2

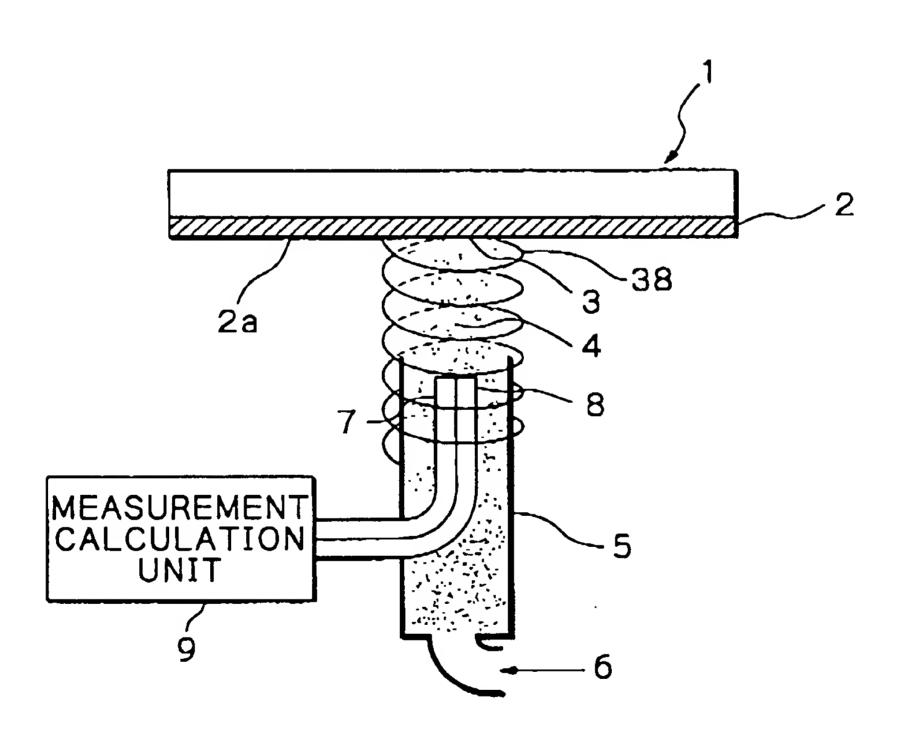
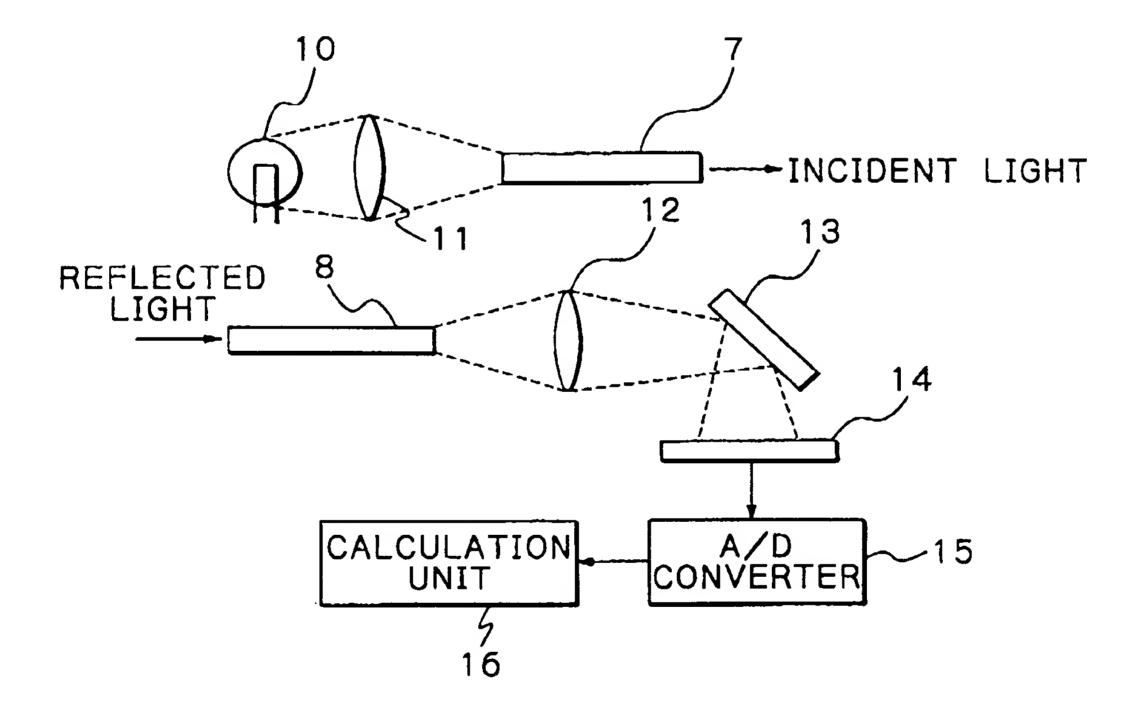
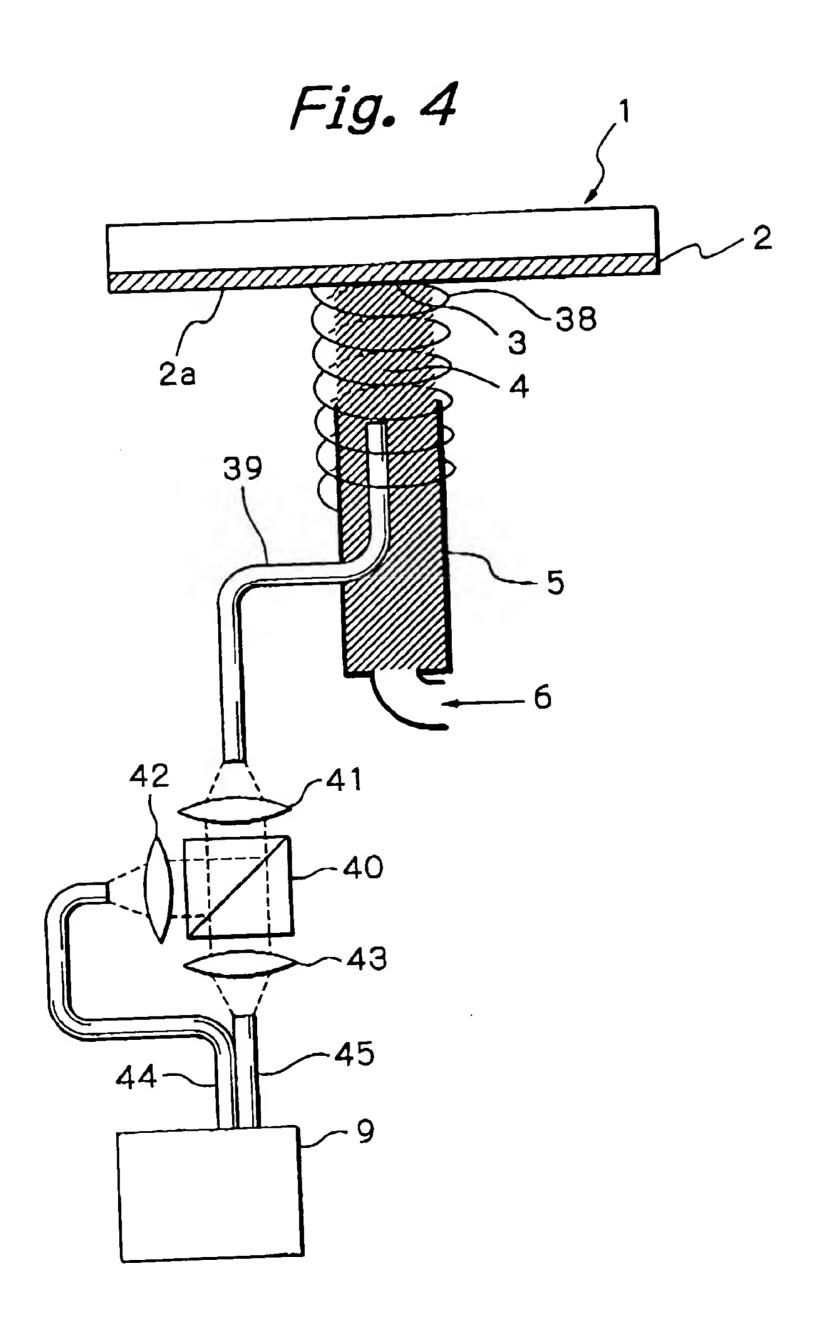
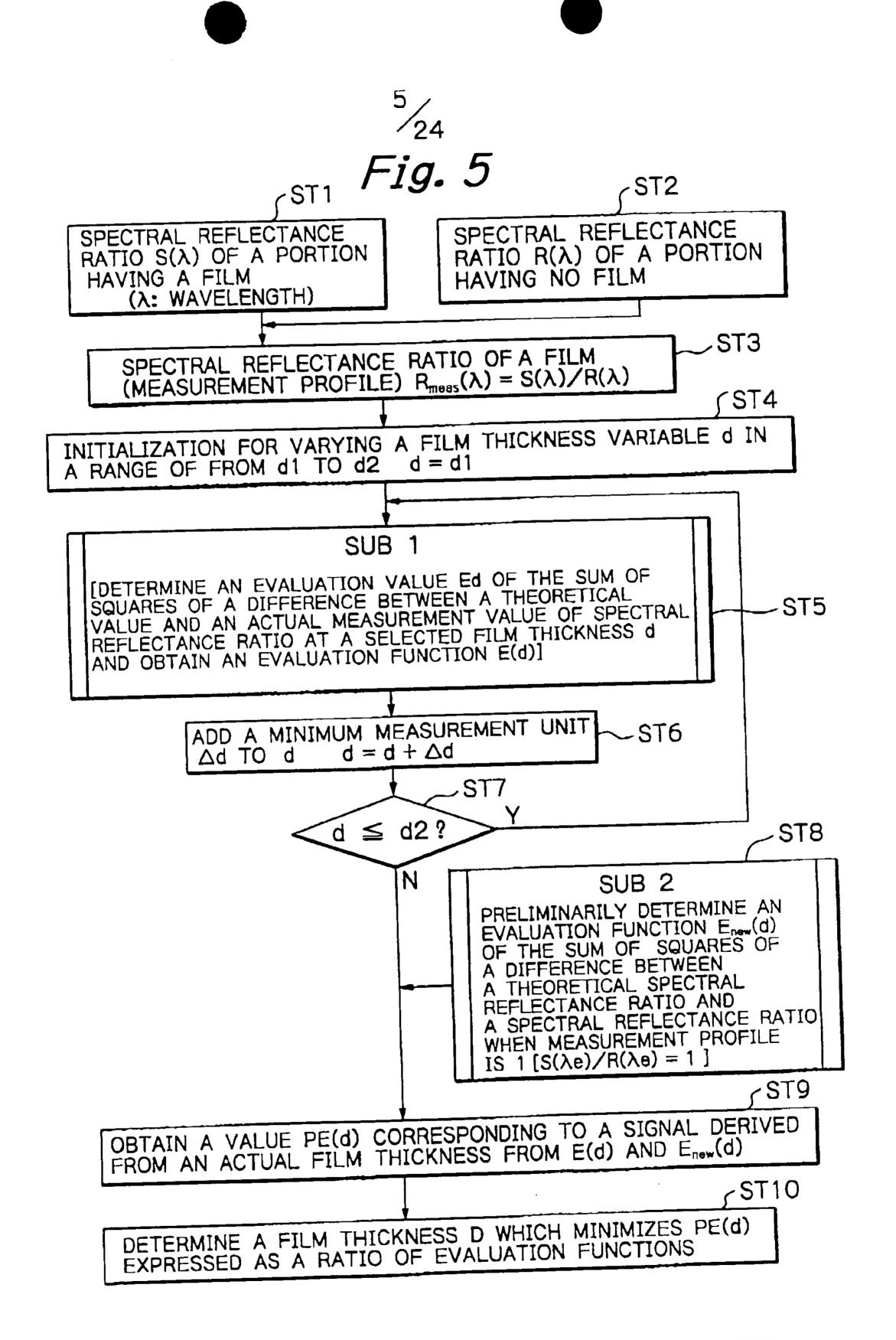
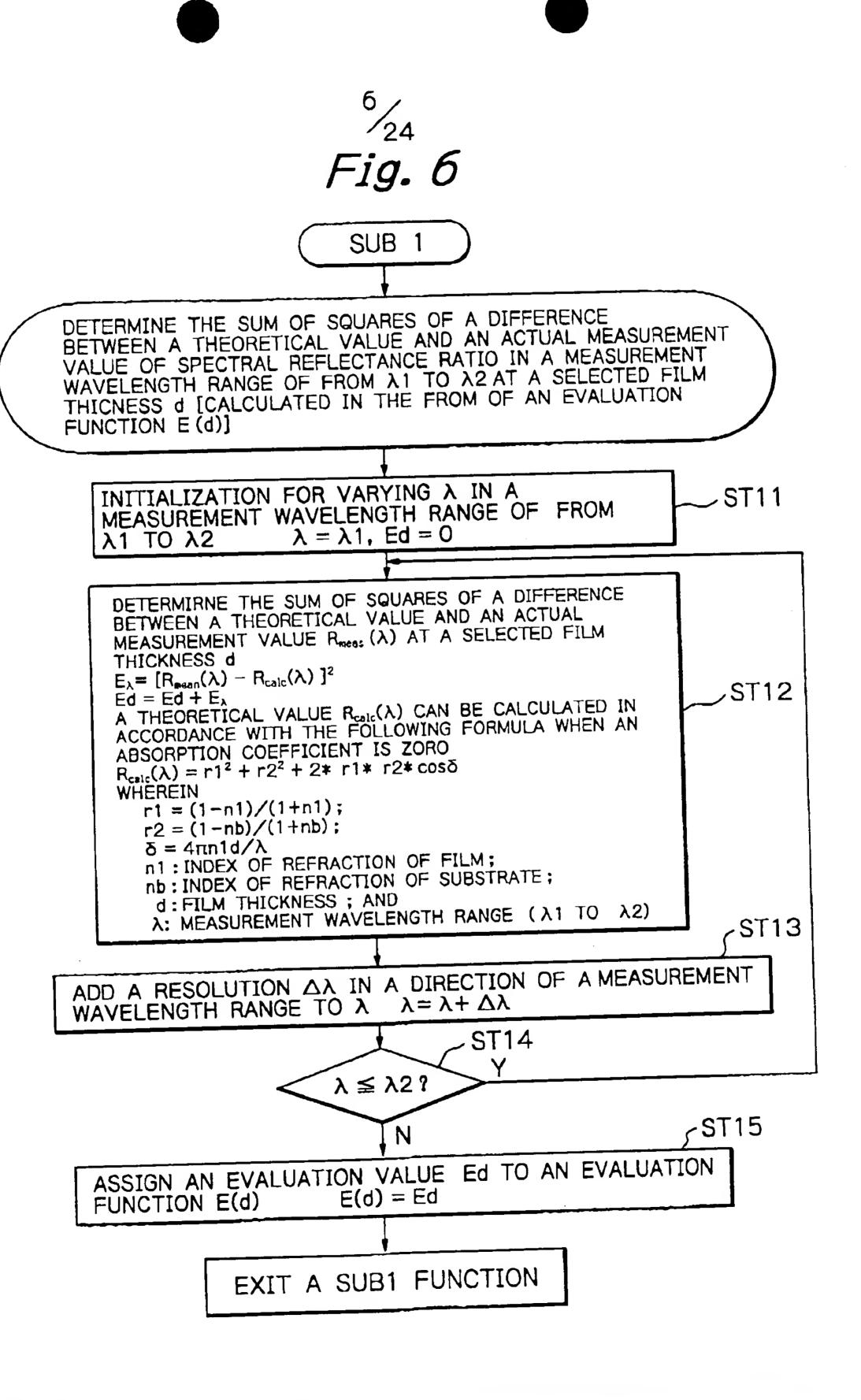


Fig. 3









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SUB 2 DETERMINE AN EVALUATION FUNCTION E (d) OF THE SUM OF SQUARES OF A DIFFERENCE BETWEEN A THEORETICAL SPECTRAL REFLECTANCE RATIO AND A SPECTRAL REFLECTANCE RATIO WHEN MEASUREMENT PROFILE IS 1 [S( $\lambda e$ )/R( $\lambda e$ ) = 1] AT A SELECTED FILM THICKNESS & IN A MEASUREMENT WAVELENGTH RANGE ( $\lambda 1$  TO  $\lambda 2$ ) **ST22** ST21 SPECTRAL REFLECTANCE SPECTRAL REFLECTANCE RATIO S(λe) OF A PORTION RATIO R(λθ) OF A PORTION HAVING A FILM HAVING NO FILM (λe: WAVELENGTH) **ST23** SPECTRAL REFLECTANCE RATIO OF A FILM (MEASUREMENT PROFILE)  $R_{moss}(\lambda e) = S(\lambda e)/R(\lambda e)$ **ST24** INITIALIZATION FOR VARYING A FILM THICKNESS VARIABLE d IN A RANGE OF FROM d1 TO d2 d=d1 SUB 3 [DETERMINE AN EVALUATION VALUE Enewd OF THE ST25 SUM OF SQUARES OF A DIFFERENCE BETWEEN A THEORETICAL VALUE AND AN ACTUAL MEASUREMENT VALUE OF SPECTRAL REFLECTANCE RATIO AT A SELECTED FILM THICKNESS d AND OBTAIN AN EVALUATION FUNCTION Enow(d)] **ST26** ADD A MINIMUM MEASUREMENT UNIT  $d = d + \Delta d$  $\Delta d$  TO d ST27  $d \leq d2$ ? IN EXIT A SUB2 FUNCTION

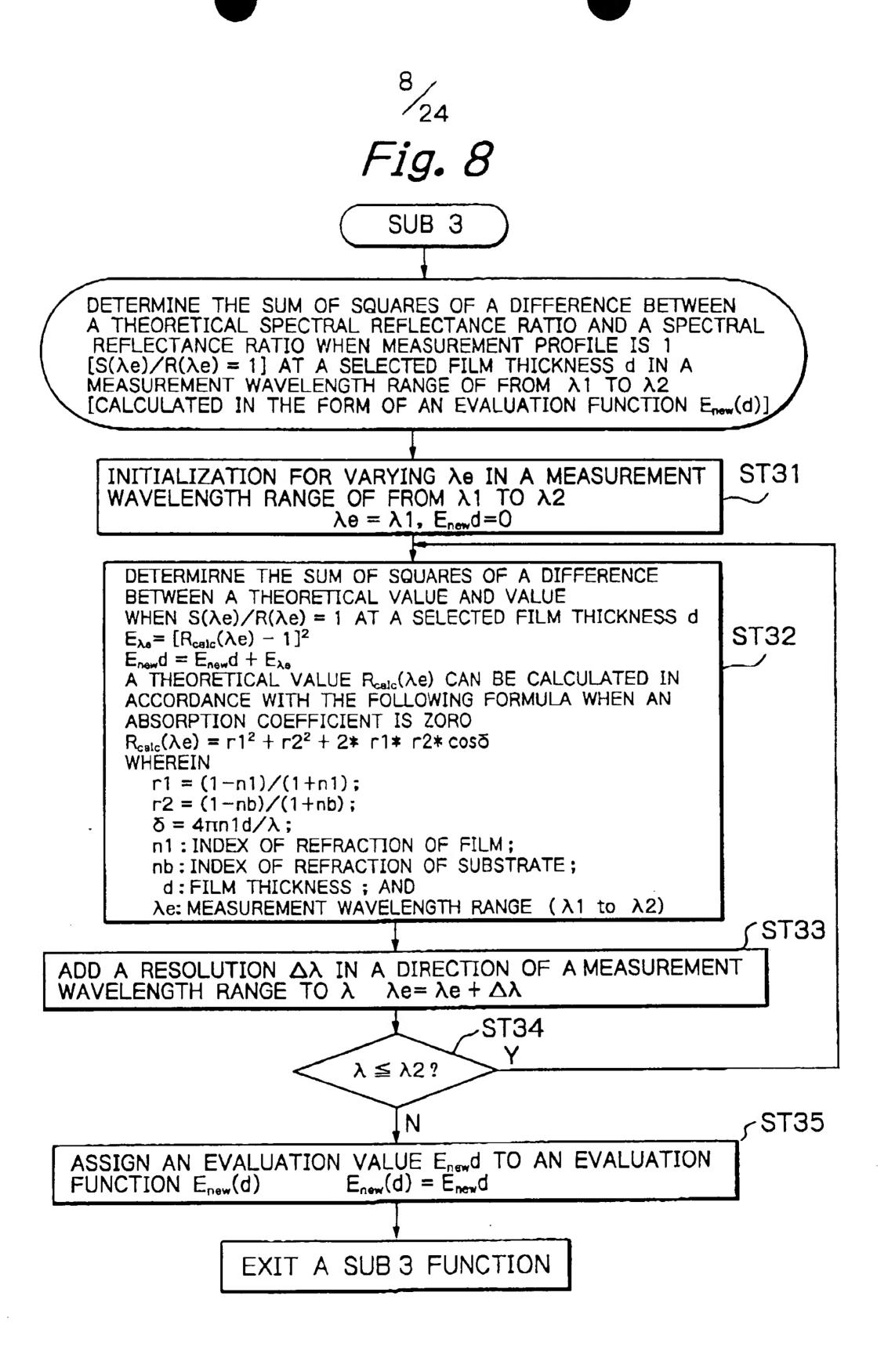


Fig. 9

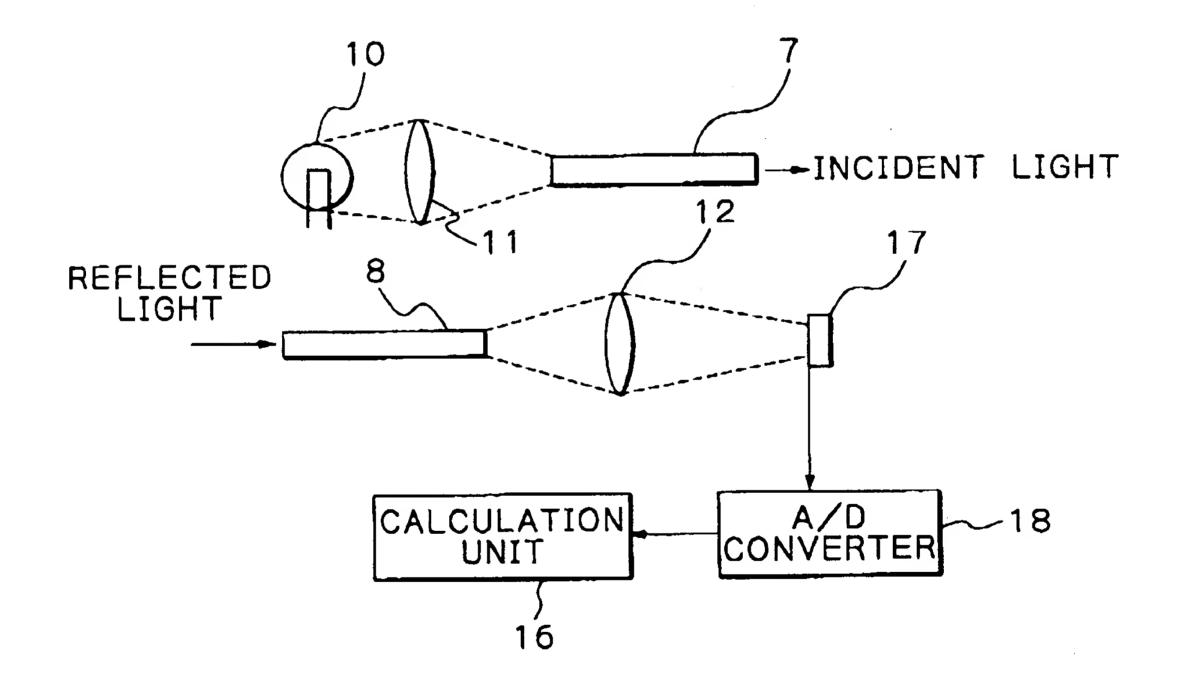
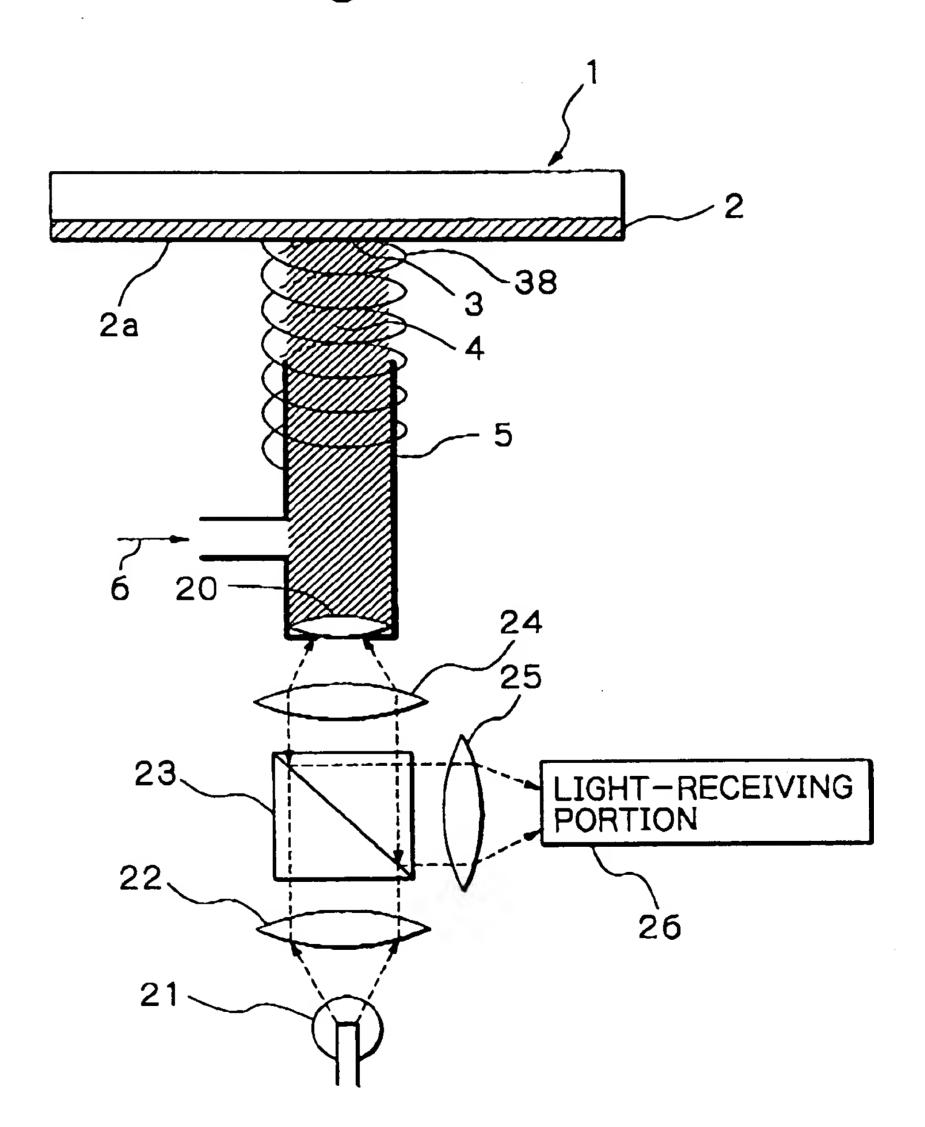


Fig. 10



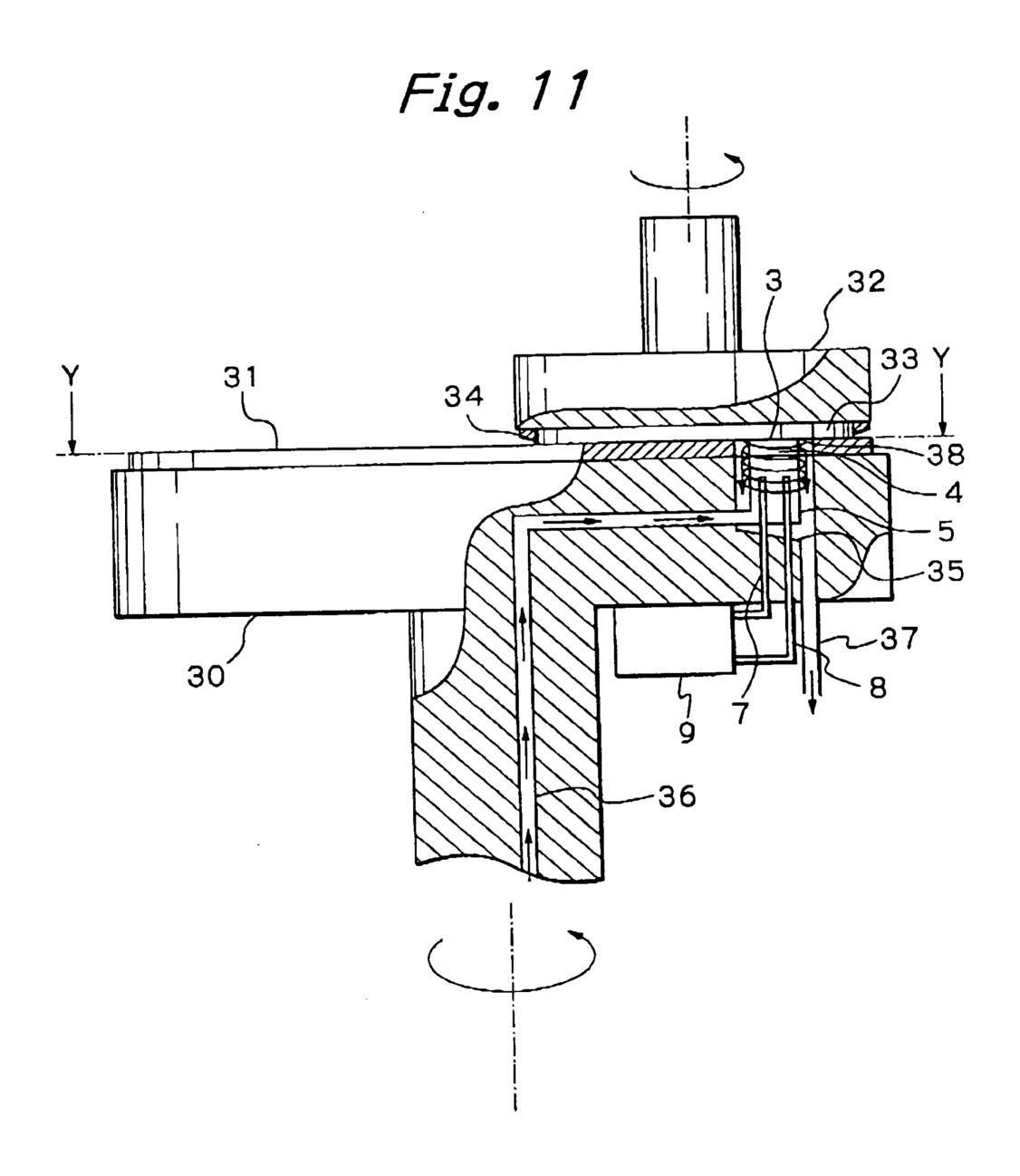
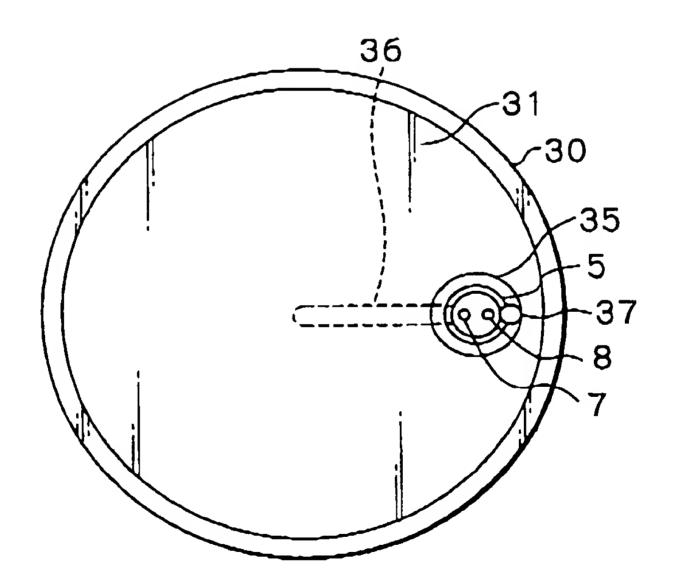
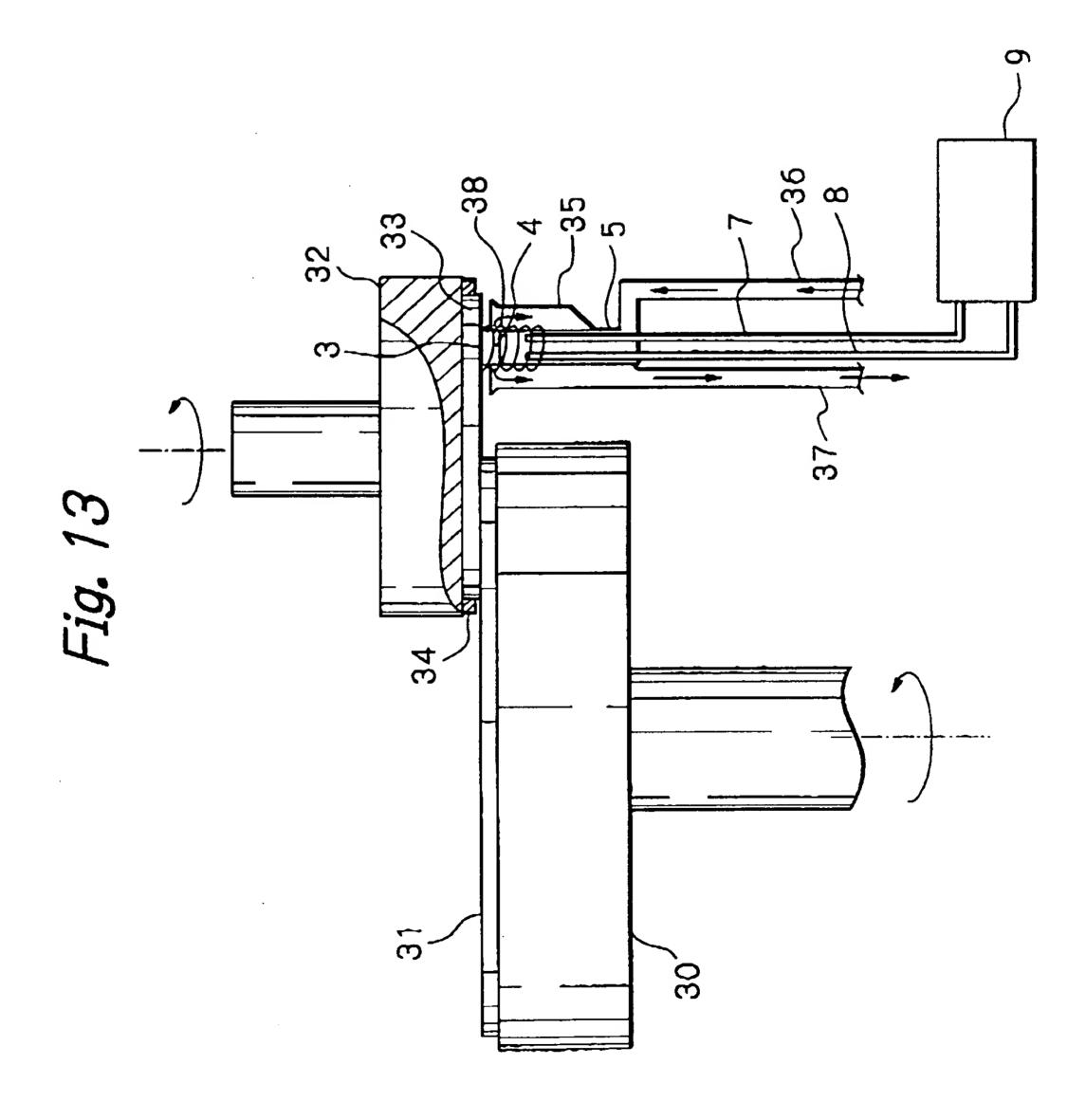


Fig. 12





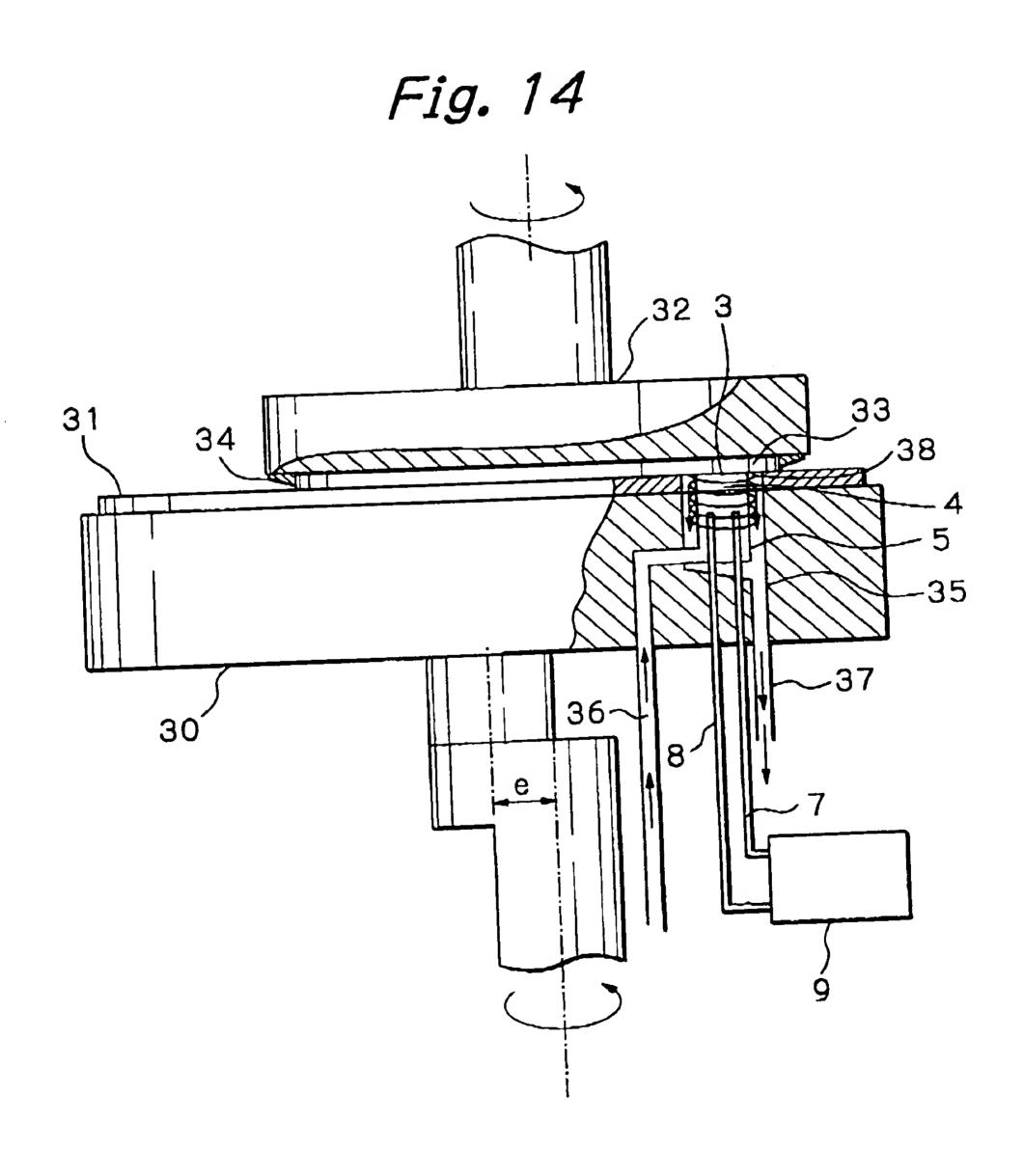
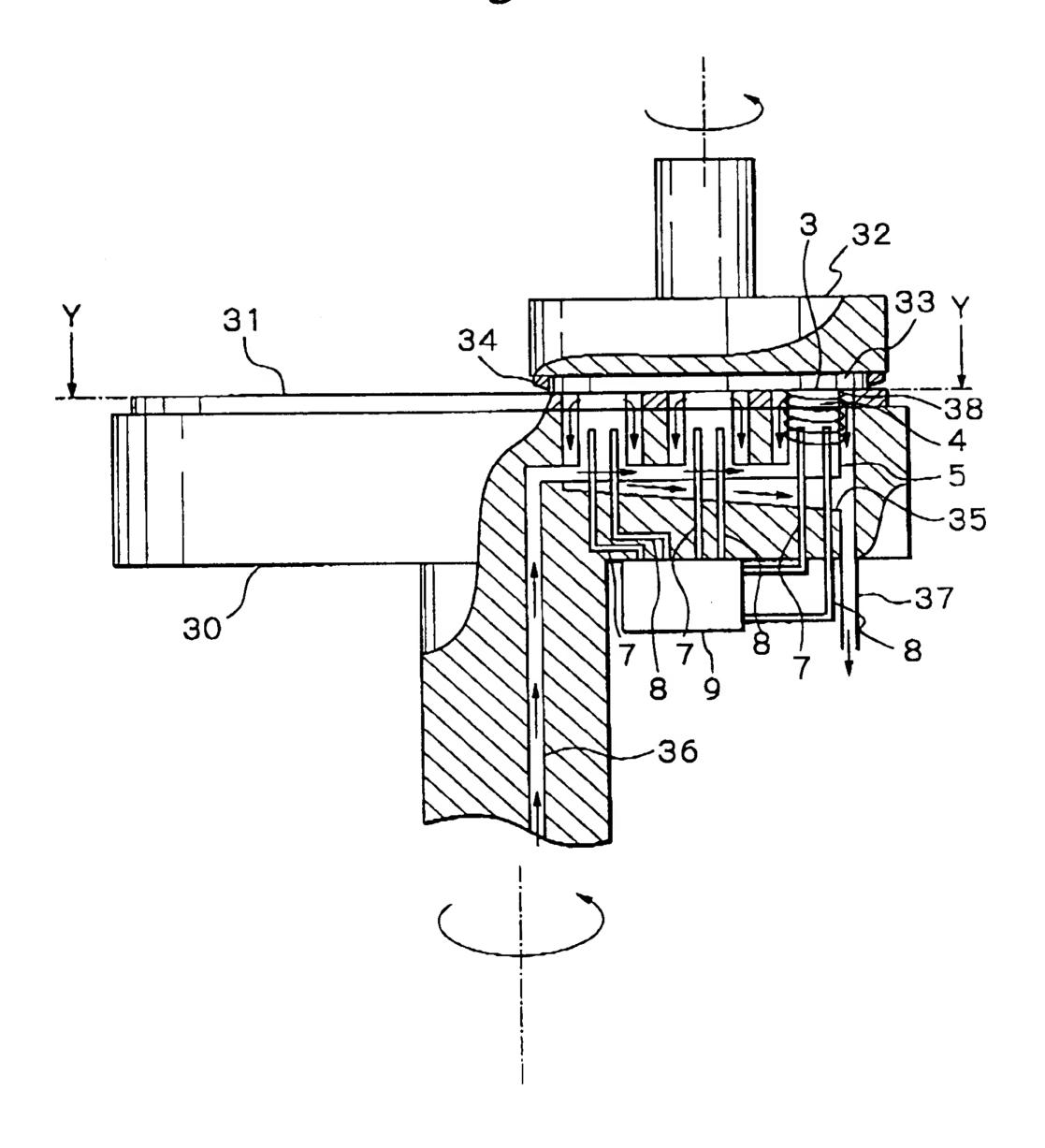
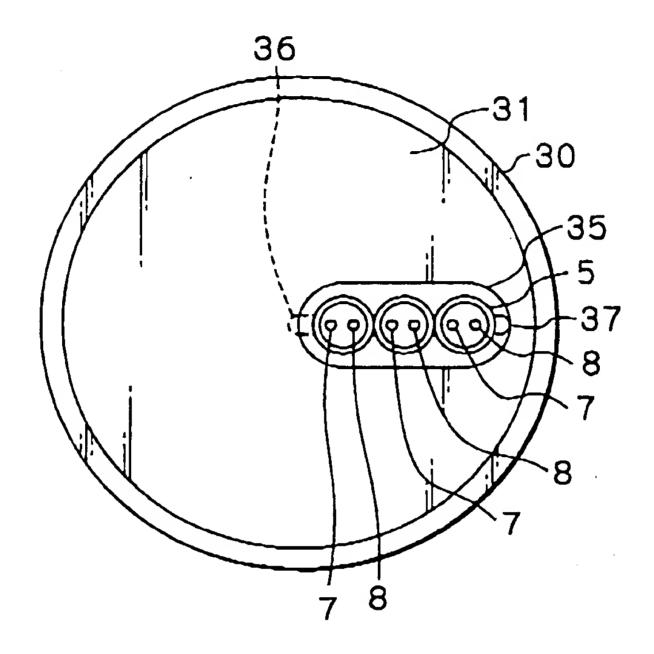


Fig. 15



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Fig. 16



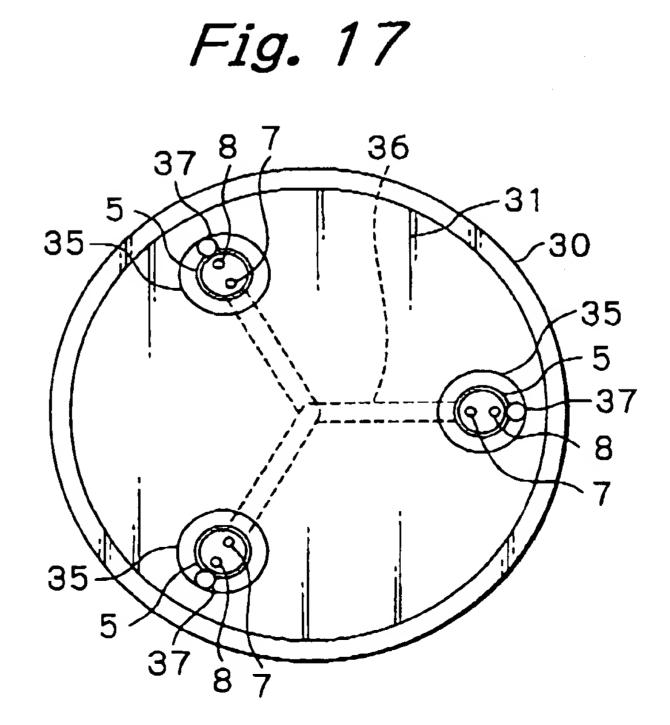


Fig. 18

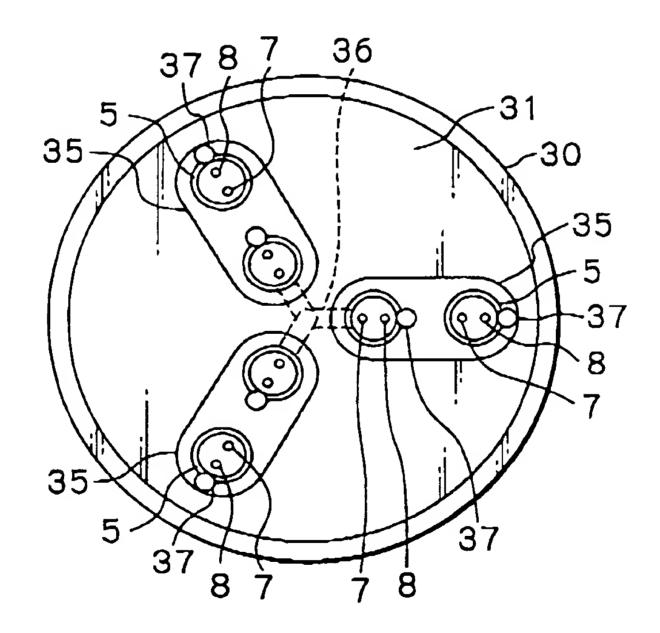


Fig. 19

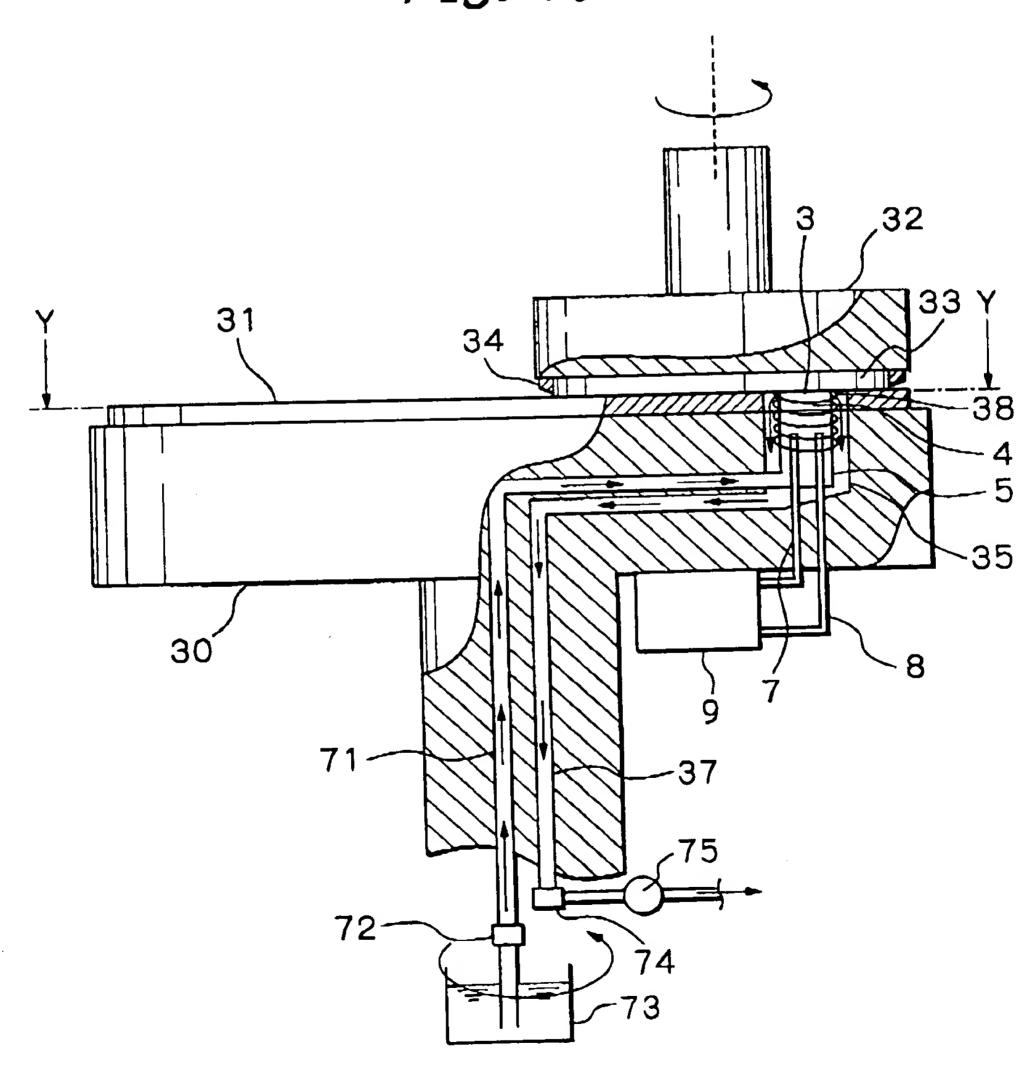
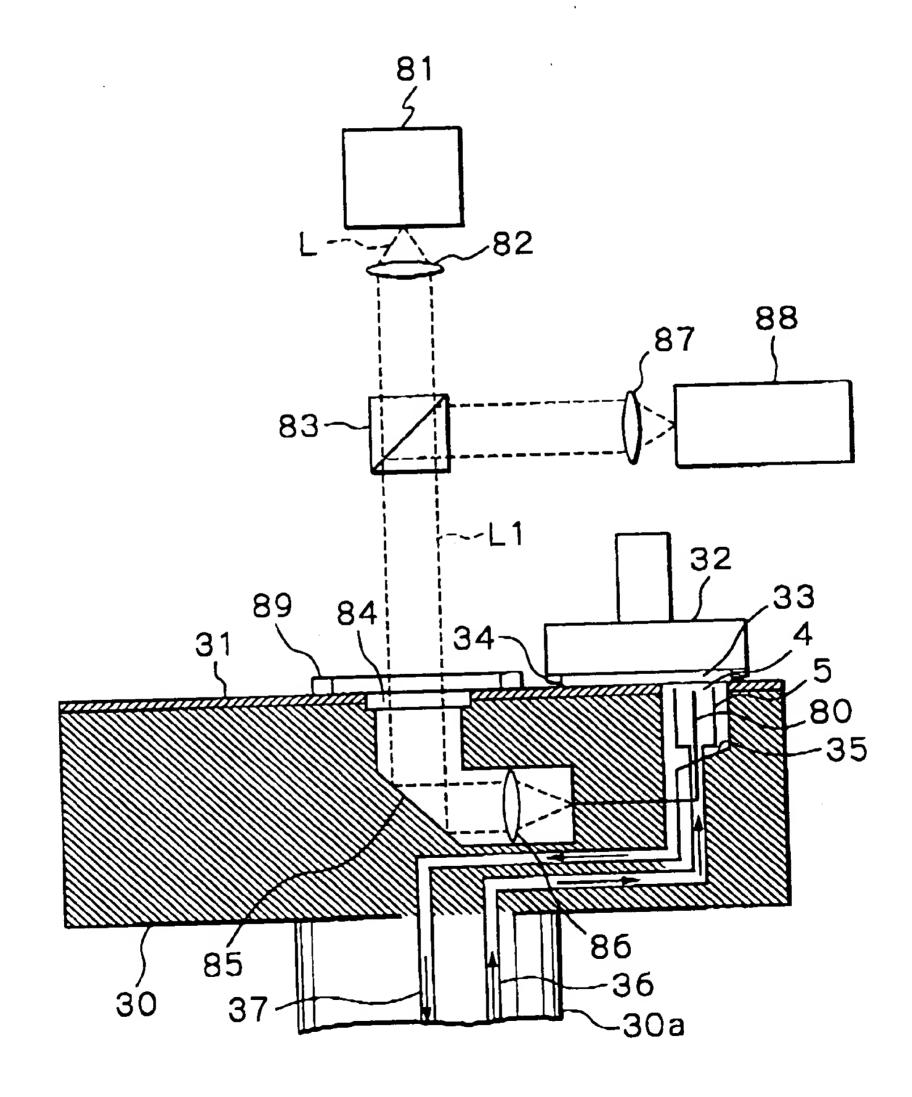
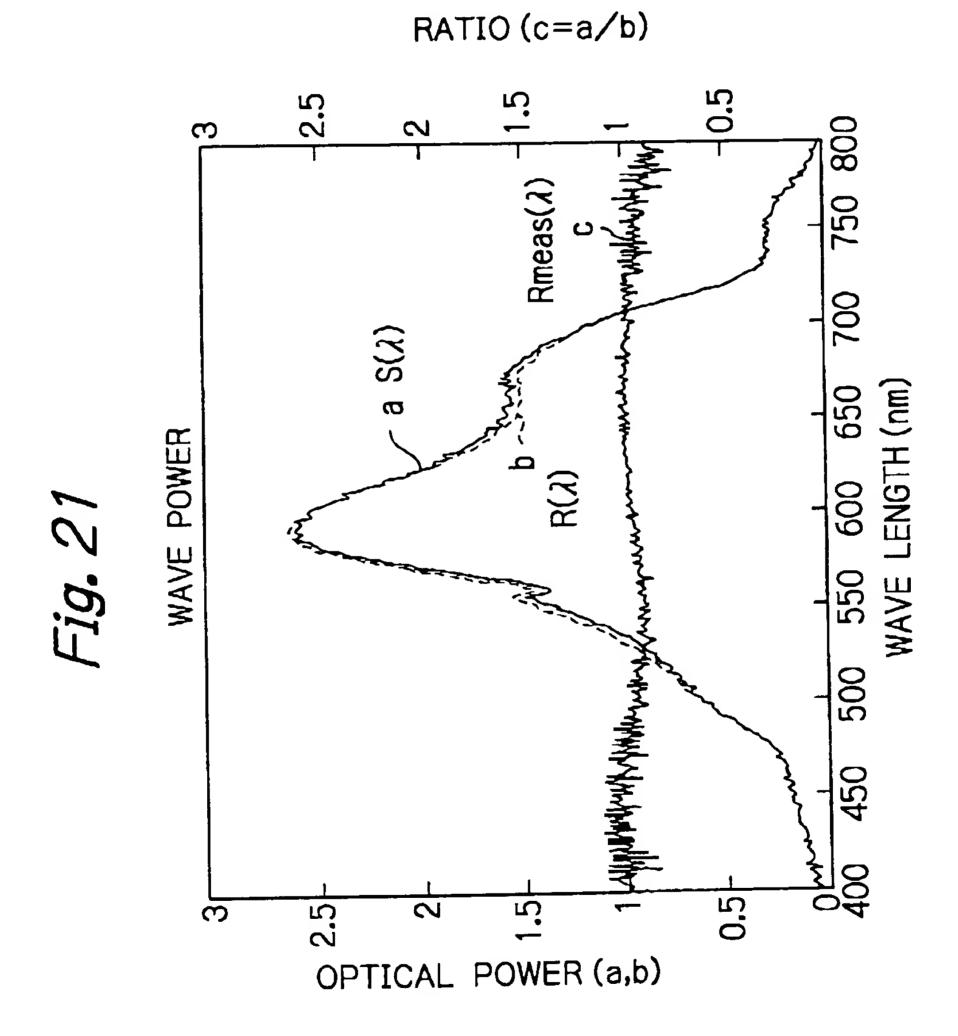


Fig. 20





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Fig. 22

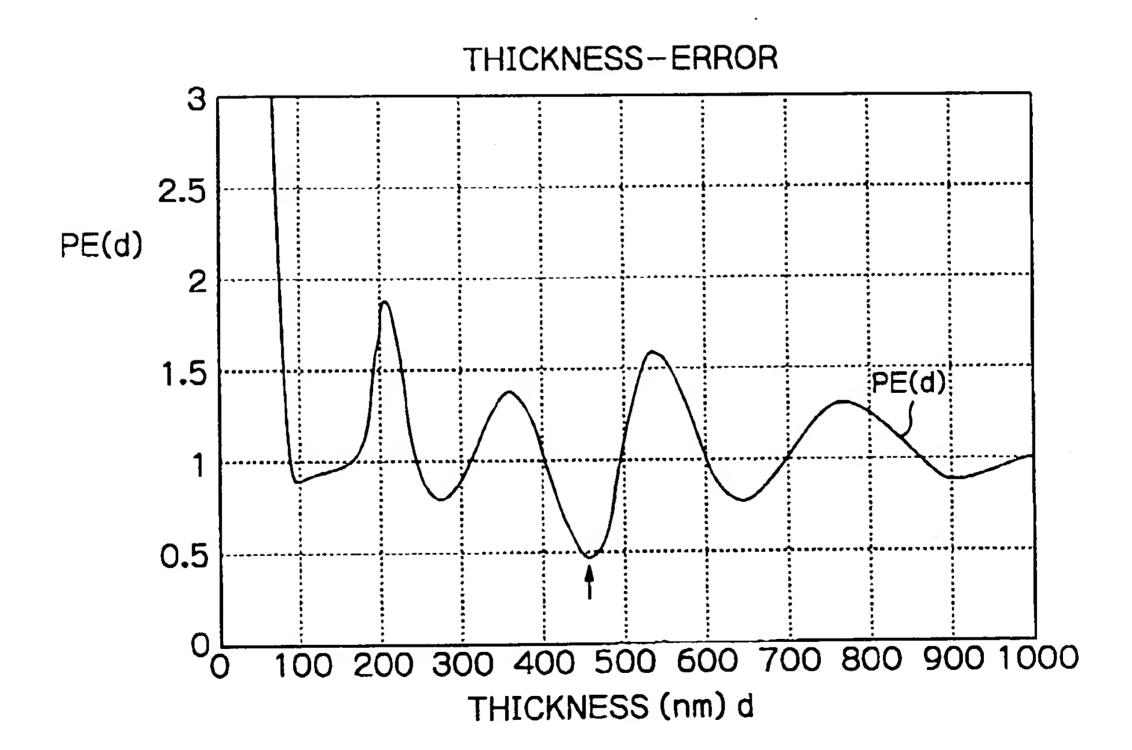


Fig. 23

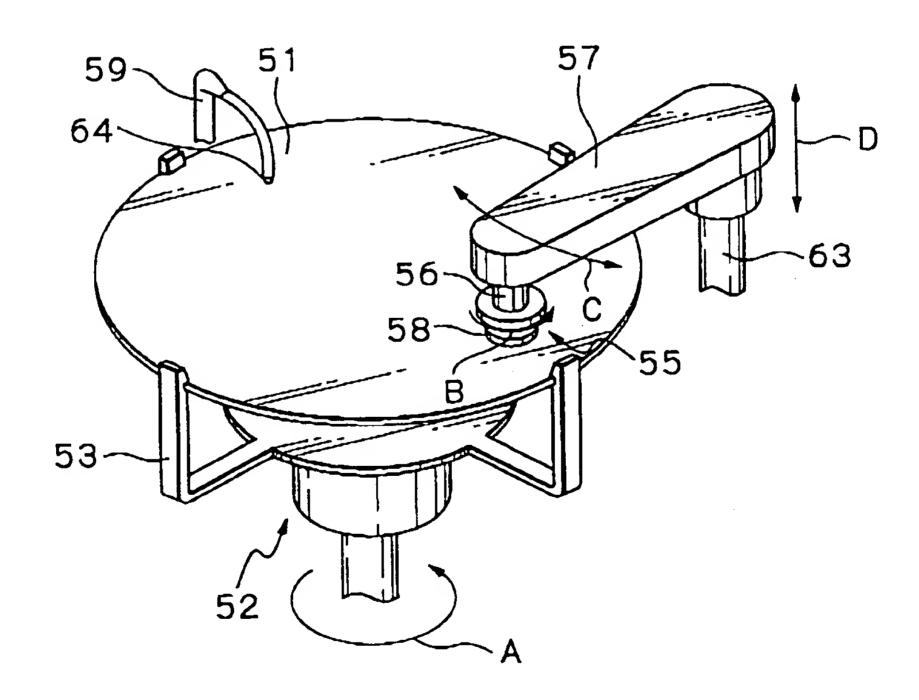


Fig. 24

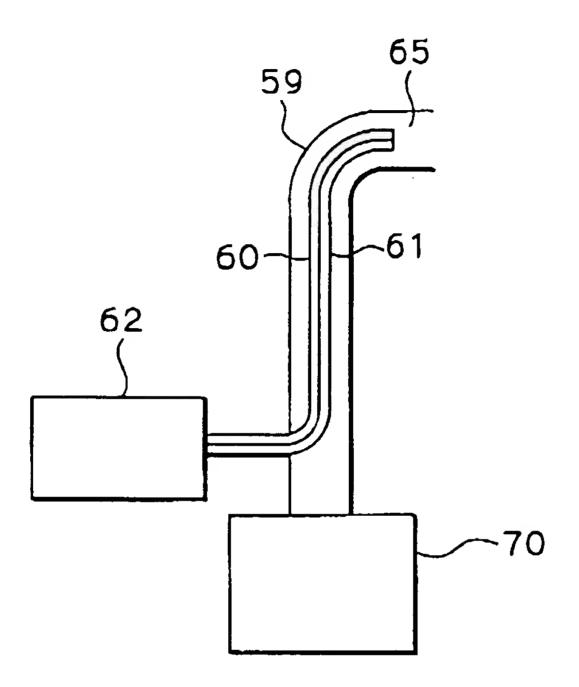
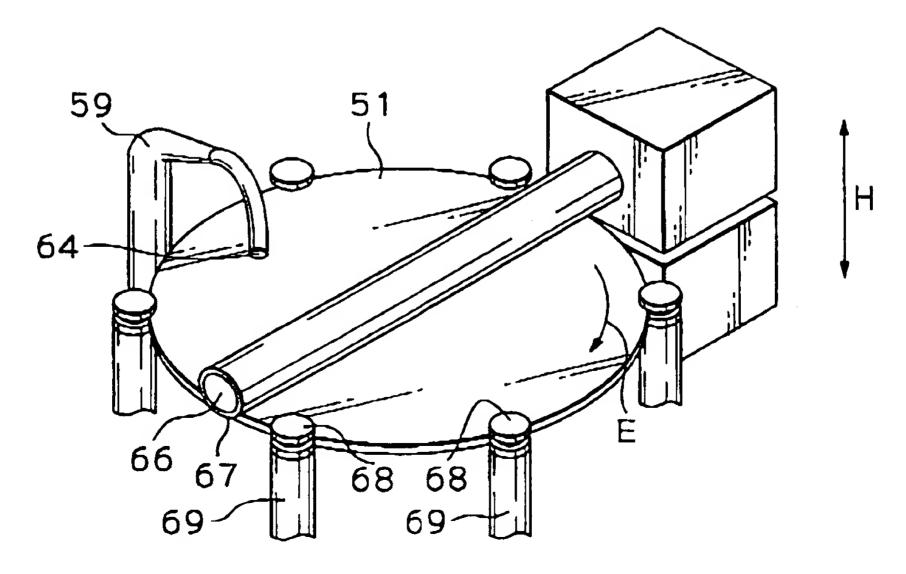


Fig. 25



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Fig. 26

